Voltus-XFi Custom Power Integrity Solution

The next-generation EM-IR solution, delivering over 3X productivity gain

Designers are actively involved in making a greener world for the future by pushing the boundaries of “low-power” enablement. Cadence is providing fast and accurate power analysis tools to enable new and revolutionary ideas on power reduction. The Cadence® Voltus™-XFi Custom Power Integrity Solution is a transistor-level electromigration and IR drop (EM-IR) tool that delivers foundry-supported SPICE-level accuracy for power integrity signoff.

Overview

Transistor-level EM-IR analysis presents unique challenges ranging from complex EM rules to the high cost of simulating large post-layout RC networks. Integrated with Cadence’s Quantus™ Extraction Solution, Spectre® X Simulator and Virtuoso® ADE Product Suite and Virtuoso Layout Suite, the Voltus-XFi solution delivers the productivity needed to reach aggressive time-to-market goals.

Benefits

Accurate and comprehensive analysis

- Widely supported in foundry process design kits (PDKs) on FinFET and FD-SOI nodes
- Native support for industry-standard syntax, netlists, abstractions, behavior, and device models
- Tightly integrated with Spectre simulators to ensure accurate analysis
- Transistor-level power grid and signal net EM-IR analysis, including accurate resistance network analysis, effective resistance, and least resistance path analysis
- Support for advanced FinFET analysis features such as self-heating effect (SHE) and failure-in-time (FIT) calculations

Improved designer productivity

- Seamlessly integrated EM-IR flow enables designers to complete analysis and debugging easily and quickly
- Integrated with Voltus IC Power Integrity Solution for advanced custom designs that have mixed transistor-level and cell-level blocks

Optimized performance for large designs

- Patented method provides accuracy and capacity with an easy-to-use model
- Distributed processing optimizes performance by distributing solving nets across multiple cores and machines with load balancing
- Persistent database for EM-IR results display is optimized for loading and viewing results in Virtuoso Layout, averaging 20X improvement in performance and 2X memory reduction over the existing solution
Integrated with Cadence ecosystem for fastest design closure

- Unified electrical signoff flow with Cadence's Tempus™ Timing Signoff Solution and Quantus Extraction
- Bring power grid design to the early stage of physical implementation with an early rail analysis capability via the Cadence Innovus™ Implementation System
- Accurate IC power integrity analysis, driven by real-world power simulation vectors, with Cadence Palladium® technology
- Benefit from chip-package-PCB co-simulation and analysis with Cadence Allegro® and Sigrity® technologies

Features

A central cockpit for EM-IR flow

An EM-IR Flow involves many different products, including extraction, design environment, circuit simulation, debugging, and layout viewing. Traditionally, designers must set up each tool and track/handle each product interaction individually, and there is no single place to check EM-IR flow consistency across all the tools. The Voltus-XFi solution solves these problems with a central EM-IR cockpit. It provides a unified setup for the flow by automatically deploying foundry-supported settings. Using the central cockpit, designers can set up and run Quantus extraction, perform EM-IR analysis on a generated or existing DSPF netlist using the Spectre simulator, and invoke and analyze results in Virtuoso Layout Suite (Figure 1).

Best-in-class use model with minimum tuning

The Spectre X and Voltus-XFi integration supports the accuracy, performance, and capacity that today’s advanced-node designs require. Like Spectre X, the Voltus-XFi solution balances an accuracy and performance tradeoff for custom IC, mixed-signal, and analog designs with a preset option. In addition, an enhanced method is used to provide a robust and accurate solution: the Spectre solver is used in the first stage, while the second stage uses a specialized RC network solver with Cadence-patented technology. The method can support larger designs and better performance than the direct method while maintaining Spectre trusted accuracy. For example, complex power-gated networks can be accurately modeled with power-gates switching during the analysis, unlike traditional approaches that model power-gates using a constant on/off resistance.

Comprehensive debugging options

The Voltus-XFi solution has a built-in option to ensure that input data are EM-IR ready. An integrated EM-IR results browser (Figure 2) summarizes the EM-IR information and highlights violations, along with details on resistance value, metal layer, width, and length information. The EM-IR results are directly annotated in Virtuoso Layout and make it easy to identify and fix the problem area.

Full chip support with Voltus integration

The Voltus-XFi solution can generate a power-grid-view (PGV) macro model for the transistor block/IP being analyzed and pass this to the Voltus IC power integrity solution for full-chip signoff. A PGV macro model is a binary model that describes an IP’s grid characteristics. It contains geometric views, port information, current information, and multi-mode multi-corner (MMMC) features in capturing various operational modes, voltages, and clock frequencies. The Voltus-XFi solution generates the most accurate views, and the Voltus IC power integrity solution applies the correct view for full-chip signoff.

Figure 1: Voltus-XFi solution enables a seamlessly integrated EM-IR flow

Figure 2: Voltus-XFi EM-IR results browser
Supported Formats

- DSPF netlist (Quantus and third-party extractors are supported)
- Spectre and SPICE netlist formats
- Spectre, SPICE, and PSpice® models
- Verilog-A 2.0 LRM-compliant behavioral models and structural netlists
- S-parameter data files in Touchstone, CITI-file, and Spectre formats
- SST2, PSF, PSF XL, and FSDB waveform formats
- Digital vector (VEC) and Verilog-Value Change Dump (VCD)
- Extended Verilog-Value Change Dump (EVCD) and digital stimulus

Cadence Services and Support

- Cadence application engineers can answer your technical questions by telephone, email, or Internet—they can also provide technical assistance and custom training.
- Cadence-certified instructors teach more than 70 courses and bring their real-world experience into the classroom.
- More than 30 Internet Learning Series (iLS) online courses allow you the flexibility of training at your own computer via the internet.
- Cadence Online Support gives you 24x7 online access to a knowledgebase of the latest solutions, technical documentation, Rapid Adoption Kits, software downloads, and more.
- For more information, please visit www.cadence.com/support for support and www.cadence.com/training for training.

Platform Support

- Build OS: RHEL 7.4
- Supported OS: RHEL 8, RHEL 7 (>=RHEL 7.4), SLES 12